

**Notice of References Cited**

Application/Control No.

10/804,722

Applicant(s)/Patent Under  
Reexamination  
CHOI ET AL.

Examiner

JASON M. MANDEVILLE

Art Unit

2629

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,897,876	05-2005	Murdoch et al.	345/589
*	B	US-7,151,517	12-2006	Lee, Baek-Woon	345/88
*	C	US-2002/0122160	09-2002	Kunzman, Adam J.	353/31
*	D	US-6,750,874	06-2004	Kim, Young-Sun	345/600
*	E	US-6,724,934	04-2004	Lee et al.	382/167
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
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	X					

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